

<b>Notice of References Cited</b>	Application/Control No. <div style="text-align: center;"><b>09/779,956</b></div>		Applicant(s)/Patent Under Reexam <div style="text-align: center;"><b>Pio</b></div>	
	Examiner <div style="text-align: center;"><b>Jack Chen</b></div>		Art Unit <div style="text-align: center;"><b>2813</b></div>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>
A				
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**FOREIGN PATENT DOCUMENTS**

	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Country	Name	Classification <sup>2</sup>
N	EP 0,996,161 A1	4/2000	EP	Patelmo et al.	----
O					
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**NON-PATENT DOCUMENTS**

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